

Search Notes

Application/Control No.

09/663,811

Examiner

Shin-Hon Chen

Applicant(s)/Patent under
Reexamination

HACHERL ET AL.

Art Unit

2131

SEARCHED

Class	Subclass	Date	Examiner
726	3	4/20/2006	S.C.
709	229	4/20/2006	S.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, PGPUB, JPO,EPO, DERWENT	4/20/2006	S.C.